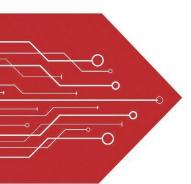
MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Broduct data sheet





S0T-89

SOT-89

Pin assignment **Package** 1 2 3

G

Α

FEATURES

- **Sensitive Gate Trigger Current**
- Low Reverse and Forward Blocking Current
- **Low Holding Current**
- Glass-Passivated Surface for Reliability and Uniformity

APPLICATIONS

- **Ignition circuits**
- Lighting ballasts
- Protection circuits
- **Switched Mode Power Supplies**

SYMBOL



ABSOLUTE MAXIMUM RATINGS

K

PARAMETER	SYMBOL	VALUE		UNIT
Repetitive Peak Off-State Voltages	V _{DRM} V _{RRM}	BT169-MS	600	V
Average On-State Current	I _{T(AV)}	0.5		Α
RMS on-State Current	I _{T(RMS)}	0.8		Α
Non-Repetitive Peak On-State Current	I _{TSM}	8		Α
Peak gate current	I _{GM}	1.0		Α
Peak Gate Power	P _{G(AV)}	0.1		W
Peak Gate Voltage	P _{GM}	2		W
Operating junction temperature	TJ	-40~+125		$^{\circ}$
Storage Temperature	T _{STG}	-40~+150		$^{\circ}$

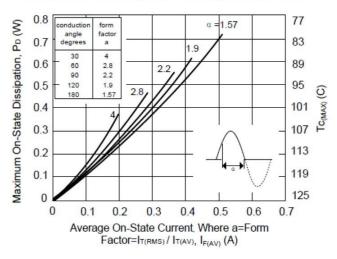


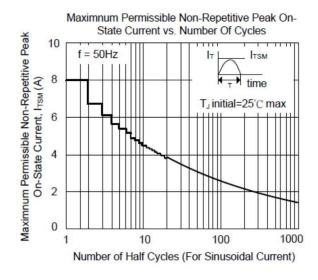
ELECTRICAL CHARACTERISTIC CURVE (TJ=25°C)

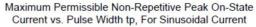
PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Peak Repetitive Forward or Reverse Blocking Current	I _{DRM} I _{RRM}	V_{AK} = Rated V_{DRM} or V_{RRM} ;			100	uA
Gate Trigger Current	I _{GT}	V _D =12V,I _T =0.1A	10		200	uA
Gate Trigger Voltage	V _{GT}	V _D =12V,I _T =0.1A			0.8	V
Peak Forward On-State Voltage	V _{TM}	$I_{T}=1.0A, I_{G}=50mA$			1.8	V
Latch Current	IL	$I_G=1.2I_{GT}$			6	mA
Holding Current	I _H	I _T =0.5mA, I _G =30mA			5	mA
Critical Rate of Rise of Off-State Voltage	dV/dt	V_D =67% V_{DRM} , R_{GK} =1 $k\Omega$,	10			V/µs

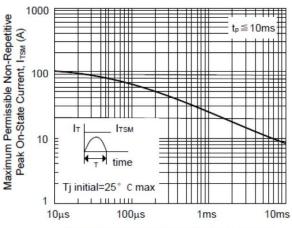
TYPICAL CHARACTERISTICS





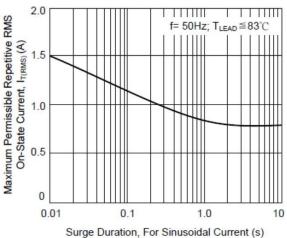




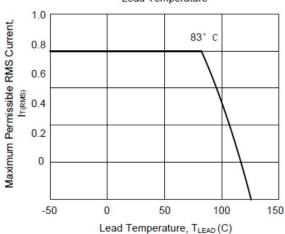


Pulse Width tp, For Sinusoidal Current, T (s)

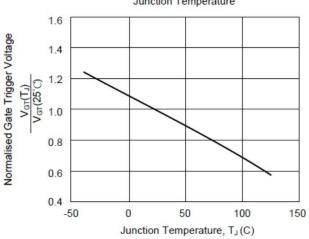
Maximum Permissible Repetitive RMS On-State Current vs. Surge Duration, For Sinusoidal Currents



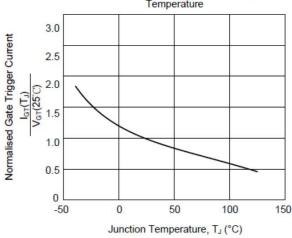
Maximum Permissible RMS Current vs. Lead Temperature



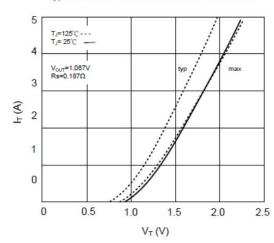
Normalised Gate Trigger Voltage vs. Junction Temperature



Normalised Gate Trigger Current vs. Junction Temperature

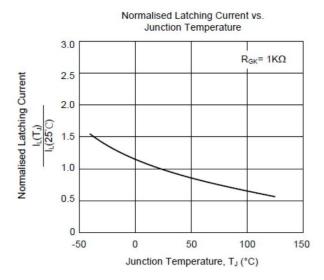


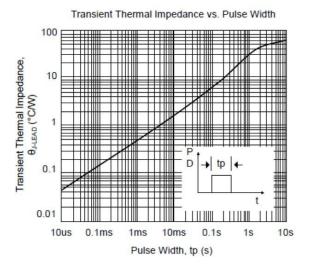
Typical And Maximum On-State Characteristic

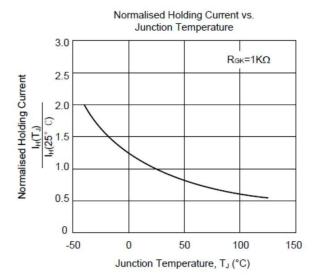


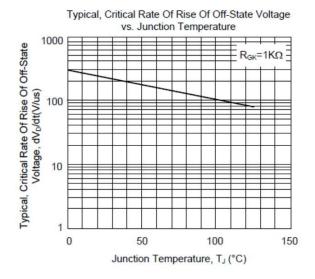
BT169-MS HF











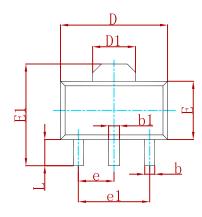


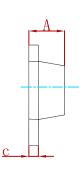




Semiconductor Compiance

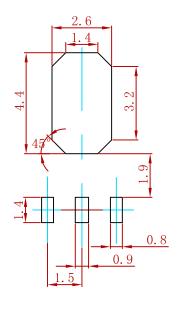
PACKAGE MECHANICAL DATA





Cumbal	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	1.400	1.600	0.055	0.063	
b	0.320	0.520	0.013	0.020	
b1	0.400	0.580	0.016	0.023	
С	0.350	0.440	0.014	0.017	
D	4.400	4.600	0.173	0.181	
D1	1.550 REF.		0.061 REF.		
E	2.300	2.600	0.091	0.102	
E1	3.940	4.250	0.155	0.167	
е	1.500 TYP.		0.060 TYP.		
e1	3.000 TYP.		0.118 TYP.		
L	0.900	1.200	0.035	0.047	

Suggested Pad Layout



- 1. Controlling dimension:in millimeters.
- 2.General tolerance:±0.05mm.
- 3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
BT169-MS	SOT-89	1000





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